

REFERENCE DESIGNATION		U.S. PATENT DOCUMENTS			
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS/ SUBCLASS	FILING DATE
					-

FOREIGN PATENT DOCUMENTS

EXAMINER		DOCUMENT			CLASS/	TRANS	LATION
INITIAL		NUMBER	DATE	COUNTRY	SUBCLASS	YES	NO
MT	A1	JP-2001229495	08/24/2001	JAPAN		X	

EXAMINER INITIAL	OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

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EXAMINER /Michael	Thier/	07/11/2006

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